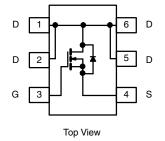


FDG410NZ-VB Datasheet N-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^{a, e} Q _g (Ty				
30	0.023 at V _{GS} = 10 V	4.5	4.2 nC			
30	0.027 at V _{GS} = 4.5 V	4.0	4.2 110			





FEATURES

- Halogen-free According to IEC 61249-2-21
 Definition
- TrenchFET[®] Power MOSFET
- Low On-Resistance
- 100 % R_q Tested
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

• DC/DC Converters, High Speed Switching

ABSOLUTE MAXIMUM RATINGS (T _A = 25 °C, unless otherwise noted)						
Parameter		Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	30	V		
Gate-Source Voltage		V _{GS}	± 20	V		
	T _C = 25 °C		4.5 ^e			
Continuous Drain Current ($T_1 = 150 \ ^{\circ}C$)	T _C = 70 °C		4.0 ^e			
Continuous Drain Current $(1) = 150^{\circ}$ C)	T _A = 25 °C	I _D	4.1 ^{b, c}			
	T _A = 70 °C		3.6 ^{b, c}	A		
Pulsed Drain Current (t = 300 µs)		I _{DM}	25			
Continuous Source-Drain Diode Current	T _C = 25 °C	L.	2.1			
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	1.1 ^{b, c}			
	T _C = 25 °C		2.5	w		
Maximum Power Dissipation	T _C = 70 °C	P _D	1.6			
	T _A = 25 °C	۲D	1.3 ^{b, c}			
	T _A = 70 °C	1	0.8 ^{b, c}			
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C		
Soldering Recommendations (Peak Tempera	ature)		260			

THERMAL RESISTANCE RATINGS								
Parameter		Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient ^{b, d}	t ≤ 5 s	R _{thJA}	75	100	°C/W			
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	40	50	0/10			

Notes:

a. Based on $T_C = 25$ °C.

b. Surface mounted on 1" x 1" FR4 board.

c. t = 5 s.

d. Maximum under steady state conditions is 166 °C/W.

e. Package limited.

COMPLIANT

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		30		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 4.8		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	0.5		2.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
		$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	μA
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 70 \text{ °C}$			10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	20			Α
		$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 3.5 \text{ A}$		0.023		
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 3 \text{ A}$		0.027		Ω
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 3.5 A		24		S
Dynamic ^b				•	<u>1</u>	
Input Capacitance	C _{iss}			424		
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		100		pF
Reverse Transfer Capacitance	C _{rss}			42		
		V_{DS} = 15 V, V_{GS} = 10 V, I_{D} = 3.5 A		8.2	13	<u> </u>
Total Gate Charge	Qg			4.2	7	nC
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 3.5 \text{ A}$		1.4		
Gate-Drain Charge	Q _{gd}			1.4		
Gate Resistance	R _g	f = 1 MHz	2.5	12.6	25.2	Ω
Turn-On Delay Time	t _{d(on)}			6	12	-
Rise Time	t _r	V_{DD} = 15 V, R_L = 3.4 Ω		20	30	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 4.4 \text{ A}, \text{ V}_{\text{GEN}} = 4.5 \text{ V}, \text{ R}_{g} = 1 \Omega$		14	21	
Fall Time	t _f			10	20	
Turn-On Delay Time	t _{d(on)}			3	6	ns
Rise Time	t _r	V_{DD} = 15 V, R_L = 3.4 Ω		11	20	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 4.4 \text{ A}, V_{GEN} = 10 \text{ V}, \text{R}_g = 1 \Omega$		20	30	
Fall Time	t _f			7	14	
Drain-Source Body Diode Characteristic	cs				<u> </u>	L
Continuous Source-Drain Diode Current	ا _S	T _C = 25 °C			2.1	
Pulse Diode Forward Current	I _{SM}				25	A
Body Diode Voltage	V _{SD}	$I_{S} = 4.4 \text{ A}, V_{GS} = 0 \text{ V}$		0.82	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			13	20	ns
Body Diode Reverse Recovery Charge	Q _{rr}			6	12	nC
Reverse Recovery Fall Time	t _a	$I_F = 4.4 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 ^\circ\text{C}$		8		1
Reverse Recovery Rise Time	t _b	-		5	1	ns

Notes:

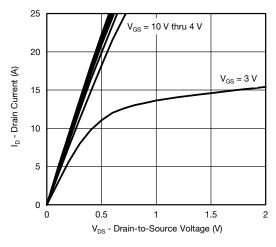
a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %. b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

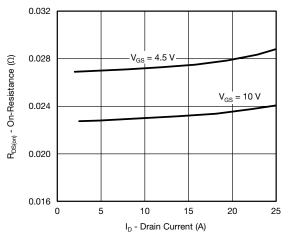
semi

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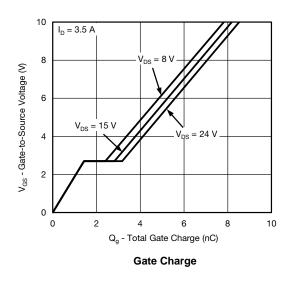


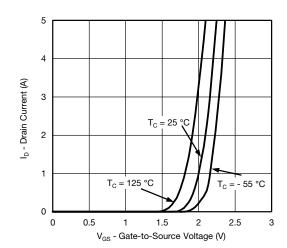




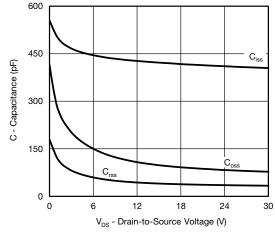


On-Resistance vs. Drain Current and Gate Voltage

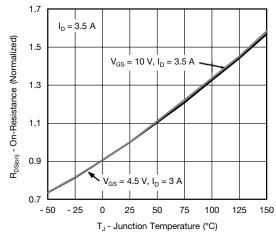




Transfer Characteristics

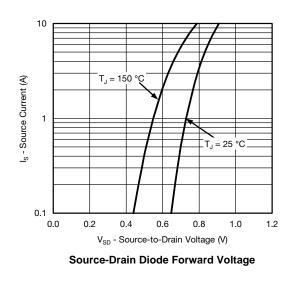


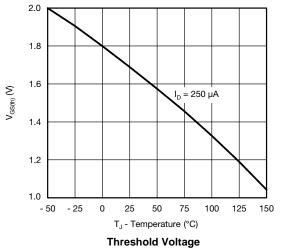


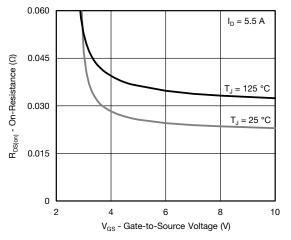


On-Resistance vs. Junction Temperature

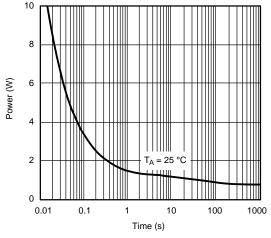




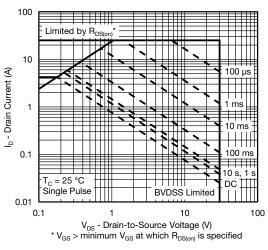




On-Resistance vs. Gate-to-Source Voltage

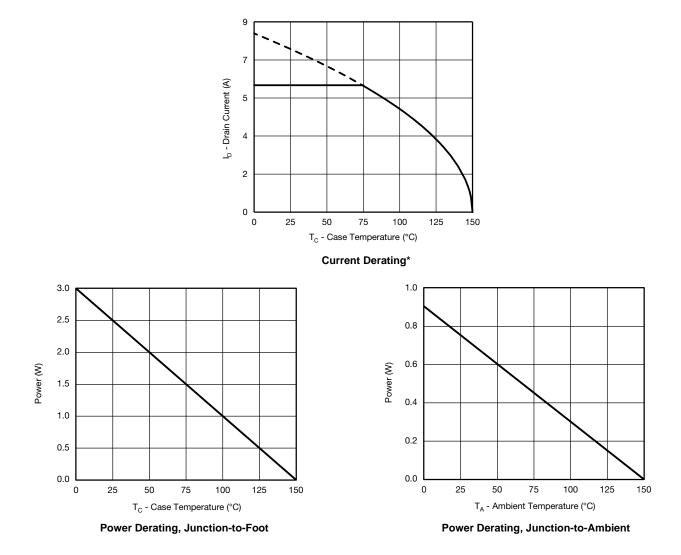


Single Pulse Power (Junction-to-Ambient)



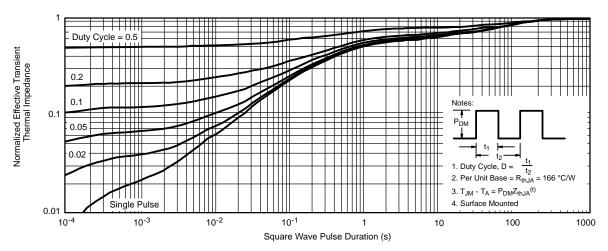
Safe Operating Area, Junction-to-Ambient



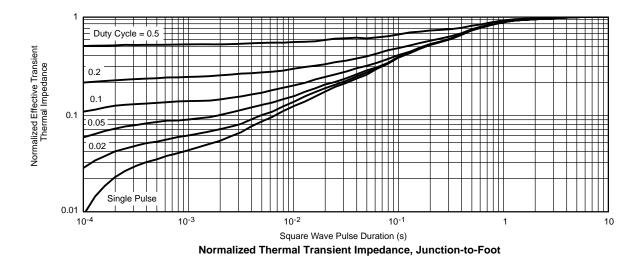


* The power dissipation P_D is based on $T_{J(max.)} = 150 \text{ °C}$, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



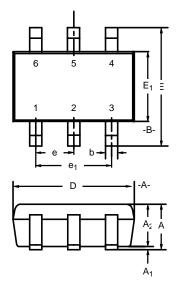


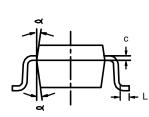
Normalized Thermal Transient Impedance, Junction-to-Ambient





SC-70: 6-LEADS





	MILLIMETERS			INCHES		
Dim	Min	Nom	Max	Min	Nom	Max
Α	0.90	-	1.10	0.035	-	0.043
A ₁	-	-	0.10	-	-	0.004
A ₂	0.80	-	1.00	0.031	-	0.039
b	0.15	-	0.30	0.006	-	0.012
С	0.10	-	0.25	0.004	-	0.010
D	1.80	2.00	2.20	0.071	0.079	0.087
E	1.80	2.10	2.40	0.071	0.083	0.094
E ₁	1.15	1.25	1.35	0.045	0.049	0.053
е	0.65BSC			0.026BSC		
e ₁	1.20	1.30	1.40	0.047	0.051	0.055
L	0.10	0.20	0.30	0.004	0.008	0.012
٩	7°Nom			7°Nom		
ECN: S-03946—Rev. B, 09-Jul-01 DWG: 5550						



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